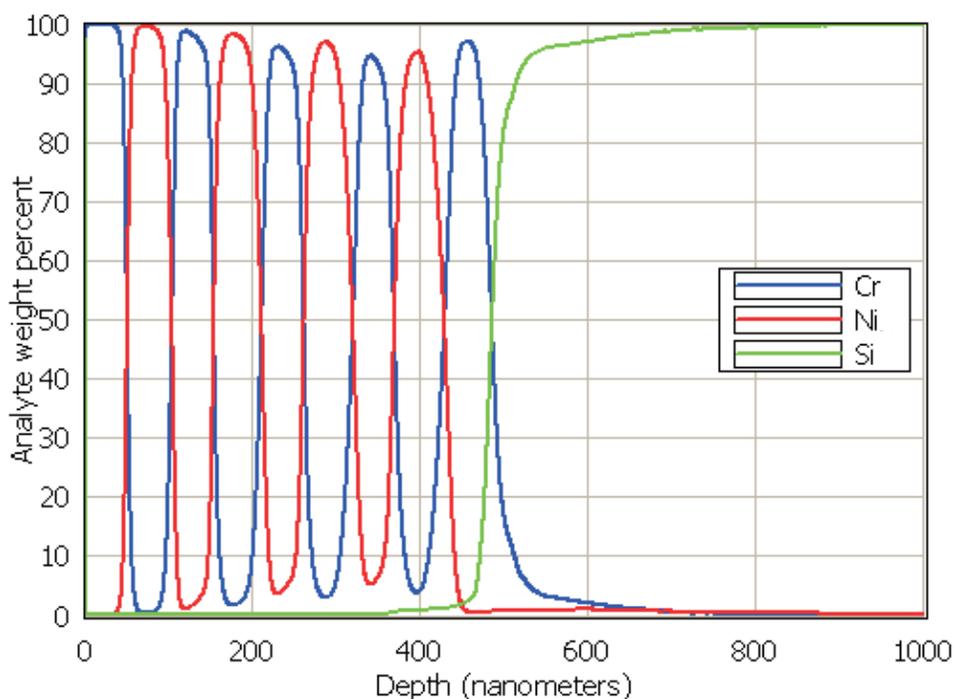


Quantitative Depth Profile (QDP) Analysis of NIST 2135c - Ni/Cr Thin Film Depth Profile Standard

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Cr1, nm	Ni1, nm	Cr2, nm	Ni2, nm	Cr3, nm	Ni3, nm	Cr4, nm	Ni4, nm	Cr5, nm	Cr $\mu\text{g}/\text{cm}^2$	Ni $\mu\text{g}/\text{cm}^2$
60	54	58	58	58	60	57	61	64	213.6	196.1

GDS-850A analysis of thin film standard certified at Cr = $206.3 \pm 13.8 \mu\text{g}/\text{cm}^2$ and Ni = $197.4 \pm 9.6 \mu\text{g}/\text{cm}^2$ with nominal layer thicknesses of Ni = 57 nm and Cr = 56 nm.

Parameters

Grimm-Style RF 4 mm Lamp
30 mA, 1000 V
Surface layers <10 s, 1000/s
Total analysis 30 s

For questions on this analysis e-mail us at: info@leco.com

For a complete listing of snapshots and performance notes visit us on the web at www.leco.com in the Spectroscopy section of the Applications Library.

